

## **Supplemental Information**

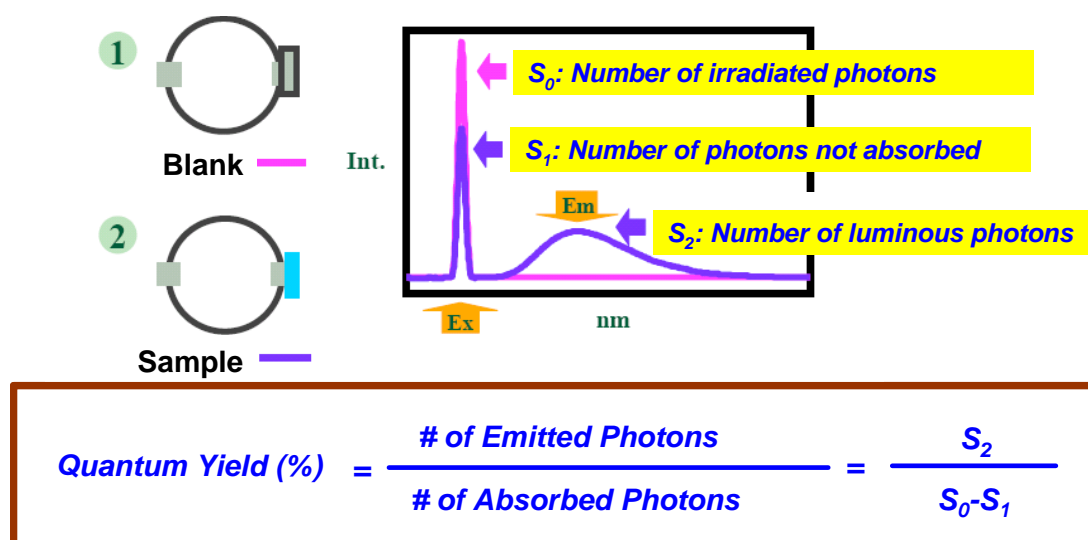
### **Synthesis and Luminescent Characteristics of Europium Dopants in SiO<sub>2</sub>/Gd<sub>2</sub>O<sub>3</sub> Core/Shell Scintillating Nanoparticles**

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Room-temperature thin-film photoluminescence was measured with a spectrophotometer (FP-6500, Jasco, Inc.) equipped with a 150W Xenon lamp source and a photomultiplier tube (PMT) detector. Quantum yield measurements of solid thin film samples used an integrating sphere (60 mm diameter; BaSO<sub>4</sub> coating; *Spectralon* reflectance standards). The quantum yield (QY) of core/shell and multi-shell scintillation nanoparticles is defined to be the percent of emitted photons versus absorbed photons, i.e.  $S_2$  divided by  $(S_0 - S_1)$  as illustrated in Fig. S1 below. Here  $S_0$  is the number of incident photons measured using a reflective standard,  $S_1$  and  $S_2$  are the number of incident photons not absorbed and luminous photons emitted by the thin film samples, respectively. All the nanoparticle samples were mixed into 500  $\mu$ L of 4 % polymethyl methacrylate (PMMA) and stirred for more than 48 hours to obtain a homogeneously mixed solution. The uniformity of the thin film is evident from the emission photos under ultra-violet (UV) excitation shown in the insets of Fig. 6. Each sample was tested at least twice in two to three different areas to ensure reproducibility of the data.



**FIGURE S1.** Schematic diagram of thin film quantum yield (QY) measurement <sup>1,2</sup>.

### References

1. A. Monkman and L.-O. Pålsson, *Adv. Mater.*, 2002, **14**, 757.
2. L. Porrès, A. Holland, L.-O. Pålsson, A. Monkman, C. Kemp and A. Beeby, *J. Fluorescence*, 2006, **16**, 267.